

3000 EMC specifications - immunity :

Port	Phenomenon	Test standard	IEC 61326-1		NAMUR NE21 : 2012		PR data sheet		PR accept test value	
			Test value	Criterion	Test value	Criterion	Test value	Criterion	Test value	Criterion
Enclosure	ESD input terminals	IEC 61000-4-2	4 kV Contact	B	6 kV Contact	B	6 kV Contact	B	6 kV Contact	B
	ESD	IEC 61000-4-2	4 kV / 8 kV Contact / Air	B	6 kV / 8 kV Contact / Air	A	6 kV / 8 kV Contact / Air	A 1%	6 kV / 8 kV Contact / Air	A 0.7%
	EM field	IEC 61000-4-3	10 V/m, 80...1000 MHz 3 V/m, 1.4...2 GHz 1 V/m, 2...2.7 GHz	A	10 V/m, 80...2000 MHz 3 V/m, 2...2.7 GHz	A	10 V/m, 80...1000 MHz 3 V/m, 1.4...2 GHz 1 V/m, 2...2.7 GHz	A 1%	10 V/m, 80...1000 MHz 3 V/m, 1.4...2 GHz 1 V/m, 2...2.7 GHz	A 0.7%
	Magnetic field	IEC 61000-4-8	30 A/m	A	100 A/m	A	30 A/m	A 0.5%	30 A/m	A 0.35%
DC power	Burst	IEC 61000-4-4	2 kV	B	2 kV	A	2 kV	A 1.0%	2 kV	A 0.7%
	Surge	IEC 61000-4-5	1 kV / 2 kV, Diff. / Comm. 0 Ω/10 Ω	B	0.5 kV / 1 kV, Diff. / Comm. 0 Ω/10 Ω	A	1 kV / 2 kV, Diff. / Comm. 0 Ω/10 Ω	A 1.0%	1 kV / 2 kV, Diff. / Comm. 0 Ω / 10 Ω	A 0.7%
	Conducted RF	IEC 61000-4-6	3 V, 150 kHz...80 MHz	A	10 V, 10 kHz...80 MHz Covers RF + LF	A	10 V, 150 kHz...80 MHz	A 0.5%	10 V, 150 kHz...80 MHz	A 0.35%
	Interruptions	IEC 61000-4-29	60% for 10 ms 100% for 20 ms	B	100% for 20 ms	A	60% for 10 ms 100% for 20 ms	B	60% for 10 ms 100% for 20 ms	B
I/O signal	Burst	IEC 61000-4-4	1 kV	B	1 kV	A	1 kV	A 1.0%	1 kV	A 0.7%
	Surge input	IEC 61000-4-5	1 kV / 2 kV, Diff. / Comm. 40 Ω	B	0.5 kV / 1 kV, Diff. / Comm. 40 Ω	B	1 kV / 2 kV, Diff. / Comm. 40 Ω	B	1 kV / 2 kV Diff. / Comm. 40 Ω	B
	Surge output	IEC 61000-4-5	1 kV / 2 kV, Diff. / Comm. 40 Ω	B	0.5 kV / 1 kV, Diff. / Comm. 40 Ω	B	1 kV / 2 kV, Diff. / Comm. 40 Ω	A 1.0%	1 kV / 2 kV Diff. / Comm. 40 Ω	A 0.7%
	Conducted RF	IEC 61000-4-6	3 V (150 kHz...80MHz)	A	10 V, 10 kHz...150 kHz	A	10 V, 150 kHz...100 MHz	A 0.5%	10 V 150 kHz...100 MHz	A 0.35%

3000 EMC specifications - emission:

- A: During testing, normal performance within the specification limits.
- B: During testing, temporary degradation, or loss of function or performance which is self recovering.
- C: During testing, temporary degradation, or loss of function or performance which requires operator intervention or system reset occurs.

Class B equipment		Standard CISPR 22	
Disturbance	Test method	Frequency range	Limits
Radiated	Quasi-peak	30 to 230 MHz	30 dB (µV/m)
		230 to 1000 MHz	37 dB (µV/m)
Conducted	Quasi-peak	0.15...0.50 MHz	40 to 30 dB (µA)
	Average		30 to 20 dB (µA)
	Quasi-peak	0.50 to 30 MHz	30 dB (µA)
	Average		20 dB (µA)